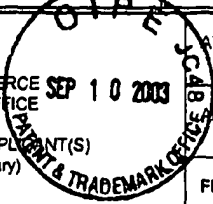


FORM PTO 1449 (modified)		ATTY DOCKET NO. <b>03500.015728.</b>		APPLICATION NO. <b>09/940,642</b>		
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		APPLICANT <b>Shinichi Kawate et al.</b>				
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)		FILING DATE <b>August 29, 2001</b>		GROUP <b>2879</b>		
Date Submitted to PTO: [DATE]						
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AIP ↓	5,982,091	11/99	Konishi	313	495	
	2002/0031972 A1	03/02	Kitamura et al.	445	3	
	6,400,091 B1	06/02	Deguchi et al.	315	169.1	
	6,472,814 B1	10/02	Yamanobe et al.	313	495	11/13/98
	5,872,422	02/99	Xu et al.	313	311	
	6,087,765	07/00	Coll et al.	313	309	
	2002/0009637A1	01/02	Murakami et al.	429	213	02/05/01
	5,847,495	12/98	Yamanobe et al.	313	310	
	5,066,883	11/91	Yoshioka et al.	313	309	
	6,455,021 B1	09/02	Saito	423	447.3	07/20/99
	6,471,936 B1	10/02	Chen et al.	423	658.2	03/02/00
	5,773,921	06/30/98	Keesman et al.	313	309	
	5,973,444	10/26/99	Xu et al.	313	309	
	5,935,639	8/10/99	Sullivan et al.	427	78	
	4,956,578	9/11/90	Shimizu et al.	315	3	
	5,185,554	2/9/93	Nomura et al.	313	495	
	6,448,709	9/02	Chuang et al.	313	497	
	↓	6,204,597	03/01	Xie et al.	313	310
EXAMINER <b>6/22</b>			DATE CONSIDERED <b>5/10/04</b>			

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<div style="font-size: 2em; font-weight: bold;">ATP</div> <div style="border-left: 2px solid black; height: 100%; margin-left: 10px;"></div>	5,577,943	11/96	Vickers et al.	445	24		
	2002/136896	09/26/00	Takikawa et al.	428	408		
	5,192,240	03/09/93	Komatsu	445	24		
	5,214,346	05/25/93	Komatsu	313	309		
	5,382,867	01/17/95	Maruo et al.	313	309		
	5,612,587	03/18/97	Itoh et al.	313	309		
	6,313,572 B1	11/06/01	Yamada	313	310		
	6,135,839	10/24/00	Iwase et al.	445	24		
	6,283,812 B1	09/01	Jin et al.	445	24		
	2001/0006232	07/05/01	Choi et al.	257	10		
	4,816,289	03/89	Komatsu et al	423	447.3		
	5,443,859	08/95	Nagata	427	122		
	5,618,875	04/97	Baker et al.	524	495		
	5,690,997	11/97	Grow	427	249.1		
	6,129,602	10/00	Yamanobe	445	24		
	6,228,904	05/01	Yadav et al.	523	210		
	6,333,016	12/01	Resasco et al.	423	447.3		
	6,413,487	07/02	Resasco et al.	423	447.3		
6,445,006	09/02	Brandes et al.	257	76			
✓	5,981,305	11/99	Hattori	438	20		
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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<div style="font-size: 2em; font-family: cursive;">ATP</div>	6,290,564	9/01	Talln et al.	445	50	
	5,458,784	10/95	Baker et al.	210	674	
	6,331,690 B1	12/01	Yudasaka et al.	219	121.6	
	5,965,267	10/99	Nolan et al.	428	408	
	6,309,612 B1	05/02	Kotaki et al.	347	85	
	5,872,541	02/99	Yoshioka et al.	345	74.1	
	5,543,684	08/96	Kumar et al.	313	495	
	5,551,903	9/96	Kumar et al.	445	24	
	4,900,483	2/90	Witzke et al.	313	309	
	5,500,200	3/96	Mandeville et al.	423	447.3	
	5,726,524	3/98	Debe	313	309	
	2002/0047562 A1	04/25/02	Kitamura et al.	315	169.3	05/29/01
	5,770,918	06/98	Kawate et al.	313	495	
	5,185,554	02/93	Nomura et al.	313	495	
	2002/0146958 A1	10/02	Ono et al.	445	24	
2003/0048056 A1	03/03	Kitamura et al.	313	311		
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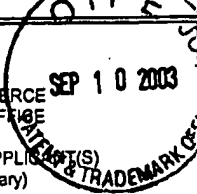
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ATP	0 535 953 B1	01/96	EPO	H01J	1/30	English
	0 290 026 B1	02/93	EPO	H01J	3/02	English
	1 122 344 A2	08/01	EPO	D01F	9/127	English
	WO 01/93292 A1	12/01	PCT	H01J	1/304	English
	WO 89/07163	08/10/89	Japan	D01F	9/12	English
	WO 90/07023	06/28/90	PCT	D01F	9/12	English
	08-115652	05/07/96	Japan	H01J	1/30	Abst. & Trans.
	0 758 028 A2	02/12/97	EPO	D01F	9/127	English
	WO 98/05920	02/12/98	PCT	G01B	7/34	English
	0 394 698 A2	10/31/90	EPO	H01J	1/30	English
	2000/277003	10/06/00	Japan	H01J	9/02	Counterpart U.S. Patent 2002/136896
	0 797 233 A2	09/24/97	EPO	H01J	1/30	English
	0 980 089 A1	02/16/00	EPO	H01J	1/30	English
	0 986 084 A2	03/15/00	EPO	H01J	1/30	English
	1 117 118 A1	07/18/01	EPO	H01J	1/312	English
✓	0 716 439 A1	06/12/96	EPO	H01J	3/02	English
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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		INVENTOR/APPLICANT <b>Shinichi Kawate et al.</b>				
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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
<b>ATP</b>	2-112125	04/24/90	JAPAN	H01J	1/30	Abst. & Counterpart U.S. Patent 4,956,978
	3-20941	01/29/91	JAPAN	H01J	31/12	Abst. & Counterpart U.S. Patent 5,185,554
	5-211029	08/20/93	JAPAN	H01J	1/30	No
	8-264109	10/11/96	JAPAN	H01J	1/30	Abst.
	9-82214	3/28/97	JAPAN	H01J	1/30	Abst. & European Equivalent 0 716 439
	1 113 478 A1	07/01	EPO	H01J	3/02	English
	09-188600	07/22/97	Japan	C30B	29/62	Abst.
	A1 443 865	08/28/91	EPO	H01J	21/10	English
	04-212236	03/08/92	Japan	H01J	1/30	Counterpart U.S. Patents 5,192,240, 5,214,346 & EP 0 443 865
	03-295131	12/26/91	Japan	H01J	1/30	Counterpart U.S. Patents 5,192,240, 5,214,346 & EP 0 443 865
	05-159696	06/25/93	Japan	H01J	1/30	Counterpart U.S. Patents 5,382,867 & EP 0 535 953
	05-198253	08/06/93	Japan	H01J	1/30	Counterpart U.S. Patents 5,382,867 & EP 0 535 953
	05-274997	10/22/93	Japan	H01J	1/30	Abst. & Counterpart U.S. Patent 5,612,587
EXAMINER <b>W. Z. S.</b>			DATE CONSIDERED <b>5/10/04</b>			

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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
AN		11-232997	08/27/99	Japan	H01J	1/30	Counterpart U.S. Patent 8,313,572 & EP 0 938 650
		A1 936 650	08/18/99	EPO	H01J	3/02	English
		10-289650	10/27/98	Japan	H01J	1/30	Counterpart U.S. Patent 8,135,839 & EP 0 871 195
		A1 871 195	10/14/98	EPO	H01J	1/30	English
		0 614 209 A1	9/94	EPO	H01J	31/12	English
		7-6714	1/95	Japan	H01J	31/12	Abst. & European Counterpart 0 614 209
		0 290 026 A1	11/88	EPO	H01J	3/02	English
		0 535 953 A2	4/93	EPO	H01J	1/30	English
		1 022 763 A1	7/00	EPO	H01J	9/02	English
		2000-223005	8/00	Japan	H01J	1/304	Abst. & Counterpart U.S. Patent 6,283,812
		0 836 217 A1	04/98	EPO	H01J	29/94	English
		WO 99/58748	11/99	PCT	D01F	9/127	English
		CN 1181607A	5/98	China			English Counterparts 0 836 217 & 99/58748
		1 187 161 A2	03/13/02	EPO	H01J	3/02	English
		1 102 299 A1	5/01	EPO	H01J	1/30	English
		1 096 533 A1	5/01	EPO	H01J	9/02	English
✓		WO 01/26130	4/01	WIPO	H01J	9/20	English
EXAMINER <i>[Signature]</i>				DATE CONSIDERED <i>5/10/04</i>			

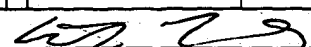
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<b>ADY</b>	GB 2 308 495 A	6/97	UK	H01J	1/20	English
	1 120 877 A1	8/01	EPO	H02G	5/06	English
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	11-162334	6/99	JAPAN	H01J	9/02	Abst.
	2000-57934	2/00	JAPAN	H01J	1/304	Abst.
	2000-86216	3/00	JAPAN	C01B	31/02	Abst.
	2000-90809	3/00	JAPAN	H01J	1/304	Abst.
	2001-288625 A	10/01	Japan	D01F	9/127	Abst., Counterpart U.S. Patent 2002/00009637 & EP 1 122 344
	0 433 507 A1	6/91	EPO	D01F	9/127	English
	03-260119	11/91	Japan	D01F	9/127	Abst. & Counterpart U.S. Patent 4,900,483
	2001-52598	2/01	Japan	H01J	1/316	Abst.
	2000-95509	4/00	Japan	C01B	31/02	Abst.
	0 451 208 B1	3/00	EPO	D01F	9/12	English
	2000-208028	7/00	Japan	H01J	1/304	Abst.
	0 936 650 A1	8/99	EPO	H01J	3/02	English
	08-298068	11/96	Japan	H01J	1/30	Abst.
<b>V</b>	2001-162600	06/19/01	Japan	B82B	1/00	Abst.

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<b>7</b>	Q. H. Wang et al., "A Nanotube-Based Field-Emission Flat Panel Display," <i>Applied Physics Letters</i> , Vol. 72, No. 22, June 1998, pp. 2912-2913				
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